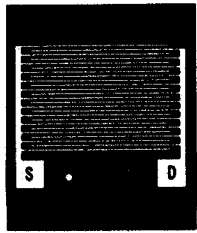


CHIP NUMBER
FN9



↑
 .030"
 (0.762mm)
 ↓

← .027"
 (0.686mm) →

Die Size: 27 x 30 (mils)
 0.686 x .0762(mm)
 4 x 4 (mils)
 Pad Size: 0.102 x 0.102(mm)
 GATE-SUBSTRATE

CONTACT METALLIZATION

Top Contact: > 12,000
 Å Aluminum

Backside Contact: 3,000 Å Gold

ASSEMBLY RECOMMENDATIONS

It is advisable that:

- a) the die be eutectically mounted with gold silicon preform 98/2%.
- b) 1 mil (0.0254mm) aluminum wire be ultrasonically attached to the top contact.

TYPICAL ELECTRICAL CHARACTERISTICS

PARAMETER	MIN.	TYP	MAX.	UNIT	TEST CONDITIONS
BV _{GSS}	-25	-30	-45	V	V _{DS} = 0, I _G = 1μA
I _{DSS}	100	400	700	mA	V _{DS} = 5V, V _{GS} = 0 (pulse test)
g _{fs}		10		mmho	V _{DG} = 10V, I _D = 2mA
I _{GSS}		-50	-500	pA	V _{GS} = -15V, V _{DS} = 0
r _{DS}	4.5	6.0	20	Ω	V _{DS} = 100mV, V _{GS} = 0
V _{GS(off)}	-0.5	5.0	12.0	V	V _{DS} = 5V, I _D = 3nA
C _{rss}		12	20	pF	V _{DG} = 10V, V _{DG} = 0, f = 1MHz
C _{iss}		25	35	pF	V _{SG} = 10V, V _{DS} = 0, f = 1MHz
ē _n		5.0		nV/√Hz	V _{DG} = 15V, I _D = 2mA, f = 10Hz

TYPICAL DEVICE TYPES: 2N5432 - 2N5434, SDF1000 series

CHIP TYPE FN9

